


<b>Search Notes</b> 	<b>Application/Control No.</b> 10672010	<b>Applicant(s)/Patent Under Reexamination</b> SHIBUYA ET AL.
	<b>Examiner</b> ALEX LIEW	<b>Art Unit</b> 2624

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SEARCH NOTES		
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382/141-152, 181-231 limited to text search	1/1/09	AL

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